ABSTRACT

ELECTRONIC COMPONENT TESTING EQUIPMENT CAPABLE OF BUFFERING TEMPERATURE OF DEVICE UNDER TEST

An electronic component testing equipment includes a testing chamber with a chuck, a buffering chamber with a pick and place member, a buffering device and horizontal and vertical displacement devices for moving the pick and place member and the buffering device respectively, and a dry air supplying device for supplying dry air into the chambers. The buffering chamber has first and second accesses for communicating with an external environment and the testing chamber respectively. The buffering device is movable by the vertical displacement device between first and second positions to correspond first or second tray thereof in position to the chuck horizontally, thereby enabling the pick and place member to horizontally transfer a device under test from the first tray to the chuck or from the chuck to the second tray. As a result, the equipment prevents the device under test from frost and brings high testing efficiency.

Figure 2